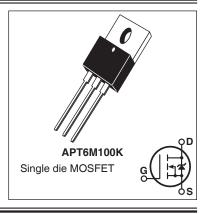




1000V, 6A, 2.50Ω Max

# N-Channel MOSFET

Power MOS  $8^{\text{TM}}$  is a high speed, high voltage N-channel switch-mode power MOSFET. A proprietary planar stripe design yields excellent reliability and manufacturability. Low switching loss is achieved with low input capacitance and ultra low  $C_{\text{rss}}$  "Miller" capacitance. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control slew rates during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency. Reliability in flyback, boost, forward, and other circuits is enhanced by the high avalanche energy capability.



## **FEATURES**

- · Fast switching with low EMI/RFI
- Low R<sub>DS(on)</sub>
- Ultra low C<sub>rss</sub> for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

## TYPICAL APPLICATIONS

- · PFC and other boost converter
- · Buck converter
- Two switch forward (asymmetrical bridge)
- Single switch forward
- Flyback
- · Inverters

## **Absolute Maximum Ratings**

Symbol	Parameter	Ratings	Unit
L	Continuous Drain Current @ T <sub>C</sub> = 25°C	6	
'D	Continuous Drain Current @ T <sub>C</sub> = 100°C	4	А
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	20	
V <sub>GS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy®	310	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	3	Α

#### **Thermal and Mechanical Characteristics**

Symbol	Characteristic	Min	Тур	Max	Unit	
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25°C			225	W	
$R_{ hetaJC}$	Junction to Case Thermal Resistance			0.43 °C/W		
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11		1 0,00	
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature Range	-55		150	- °C	
T <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W <sub>T</sub>	Package Weight		0.07		oz	
			1.2		g	
Torque	Mounting Torque ( TO-220 Package), 6-32 or M3 screw		·	10	in·lbf	
				1.1	N·m	

#### **Static Characteristics**

# T<sub>J</sub> = 25°C unless otherwise specified

Δ	PΊ	<b>[6</b> ]	Μ¹	10	n	K
$\overline{}$		v	IVI	ıv	u	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$	1000			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> = 250μA		1.15		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance®	$V_{GS} = 10V, I_{D} = 3A$		2.05	2.50	Ω
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	\/ -\/   -1mA	3	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_{D} = 1mA$		-10		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 1000V$ $T_{J} = 25^{\circ}C$			100	μA
		$V_{GS} = 0V$ $T_J = 125^{\circ}C$			500	] μΑ
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±30V			±100	nA

# **Dvnamic Characteristics**

# $T_{\rm J} = 25^{\circ}$ C unless otherwise specified

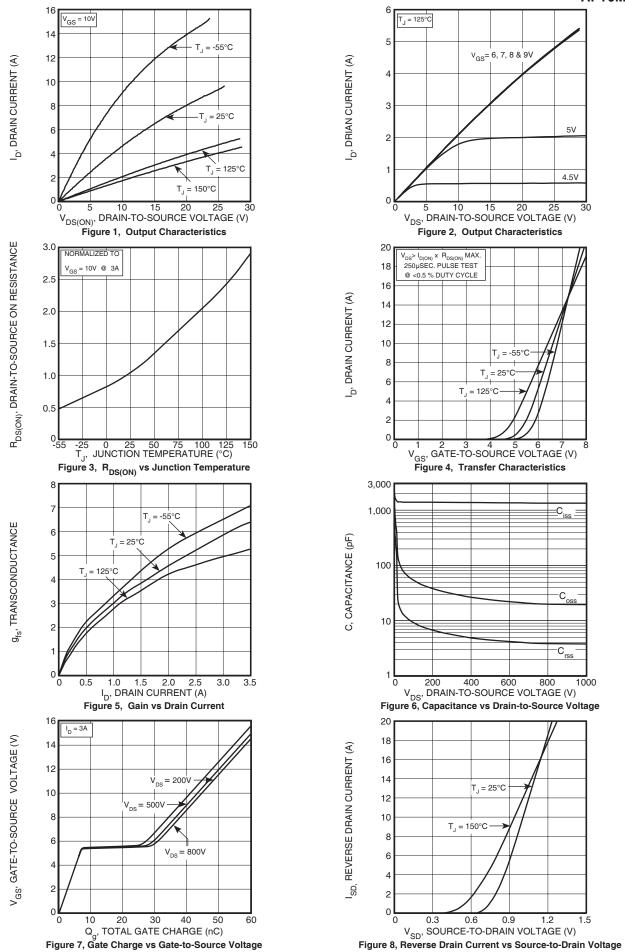
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
g <sub>fs</sub>	Forward Transconductance	$V_{DS} = 50V, I_{D} = 3A$		5.6		S
C <sub>iss</sub>	Input Capacitance	V 0V V 05V		1410		
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		19		
C <sub>oss</sub>	Output Capacitance	1 - 11/11/12		120		
C <sub>o(cr)</sub> ⊕	Effective Output Capacitance, Charge Related	V 0V V 0V 00TV		48		pF
C <sub>o(er)</sub> ⑤	Effective Output Capacitance, Energy Related	$V_{GS} = 0V$ , $V_{DS} = 0V$ to 667V		25		
$Q_g$	Total Gate Charge			43		
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 3A,$		8		nC
$Q_{gd}$	Gate-Drain Charge	$V_{DS} = 500V$		21		
t <sub>d(on)</sub>	Turn-On Delay Time	Resistive Switching		6.4		
t <sub>r</sub>	Current Rise Time	V <sub>DD</sub> = 667V, I <sub>D</sub> = 3A		5.8		no
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G} = 10\Omega^{\textcircled{6}}, V_{GG} = 15V$		22		ns
-t <sub>f</sub>	Current Fall Time	1		5.4		

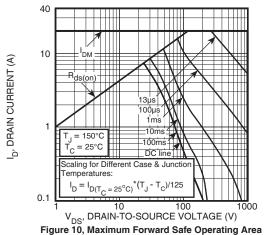
### **Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I <sub>s</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n			6	А
I <sub>SM</sub>	Pulsed Source Current (Body Diode) (1)	integral reverse p-n junction diode (body diode)			20	^
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 3A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.0	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 3A, V <sub>DD</sub> = 100V <sup>③</sup>		1025		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$di_{SD}/dt = 100A/\mu s$ , $T_J = 25$ °C		17		μC
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 3A$ , di/dt $\le 1000A/\mu s$ , $V_{DD} = 667V$ , $T_J = 125^{\circ}C$			10	V/ns

- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at  $T_J = 25$ °C, L = 68.89mH,  $R_G = 10\Omega$ ,  $I_{AS} = 3A$ .
- 3 Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- $\begin{array}{l} \textcircled{4} \quad \textbf{C}_{o(cr)} \text{ is defined as a fixed capacitance with the same stored charge as } \textbf{C}_{OSS} \text{ with } \textbf{V}_{DS} = 67\% \text{ of } \textbf{V}_{(BR)DSS}. \\ \textcircled{5} \quad \textbf{C}_{o(er)} \text{ is defined as a fixed capacitance with the same stored energy as } \textbf{C}_{OSS} \text{ with } \textbf{V}_{DS} = 67\% \text{ of } \textbf{V}_{(BR)DSS}. \\ \textbf{To calculate } \textbf{C}_{o(er)} \text{ for any value of } \textbf{V}_{DS} \text{ less than } \textbf{V}_{(BR)DSS}, \text{ use this equation: } \textbf{C}_{o(er)} = -4.09\text{E-8/V}_{DS}^2 + 7.21\text{E-9/V}_{DS} + 1.40\text{E-11}. \\ \end{array}$
- 6 R<sub>G</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.





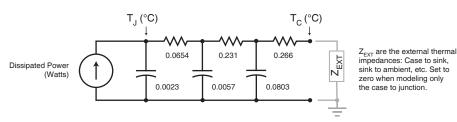
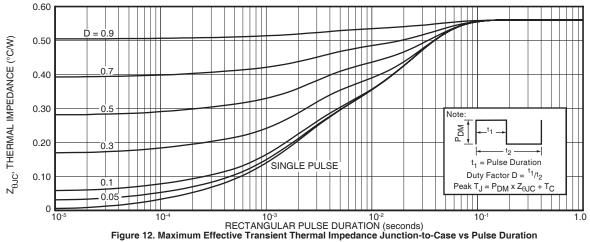


Figure 11, Transient Thermal Impedance Model



# TO-220 (K) Package Outline

